

**Search Notes**

Application/Control No.

10/807,880

Examiner

Huyen Le

Applicant(s)/Patent under  
Reexamination

MCEWAN, WAYNE E.

Art Unit

3751

**SEARCHED**

Class	Subclass	Date	Examiner
401	268 282 289 290	12/23/2005	HL
	136-140		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR